

Advances in GaN Power ICs: Efficiency, Reliability & Autonomy



Dan Kinzer, Co-Founder, COO / CTO
dan.kinzer@navitassemi.com



Navitas

Energy • Efficiency • Sustainability





[Read More](#)



The Enabling Force



20x

Faster
Switching

3x

Smaller &
Lighter

Up To
40%

Energy Savings

Up To
3x

Higher
Power Density

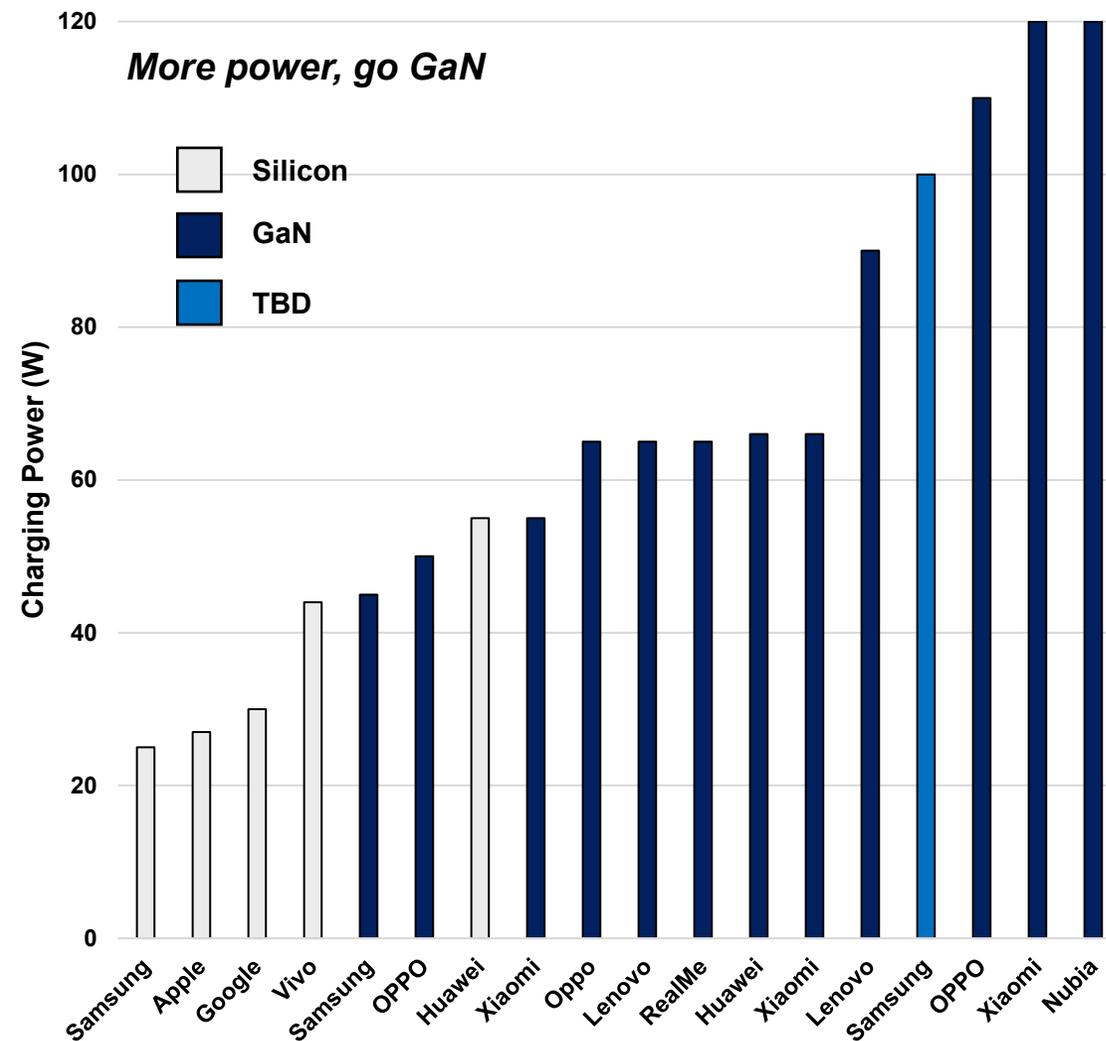
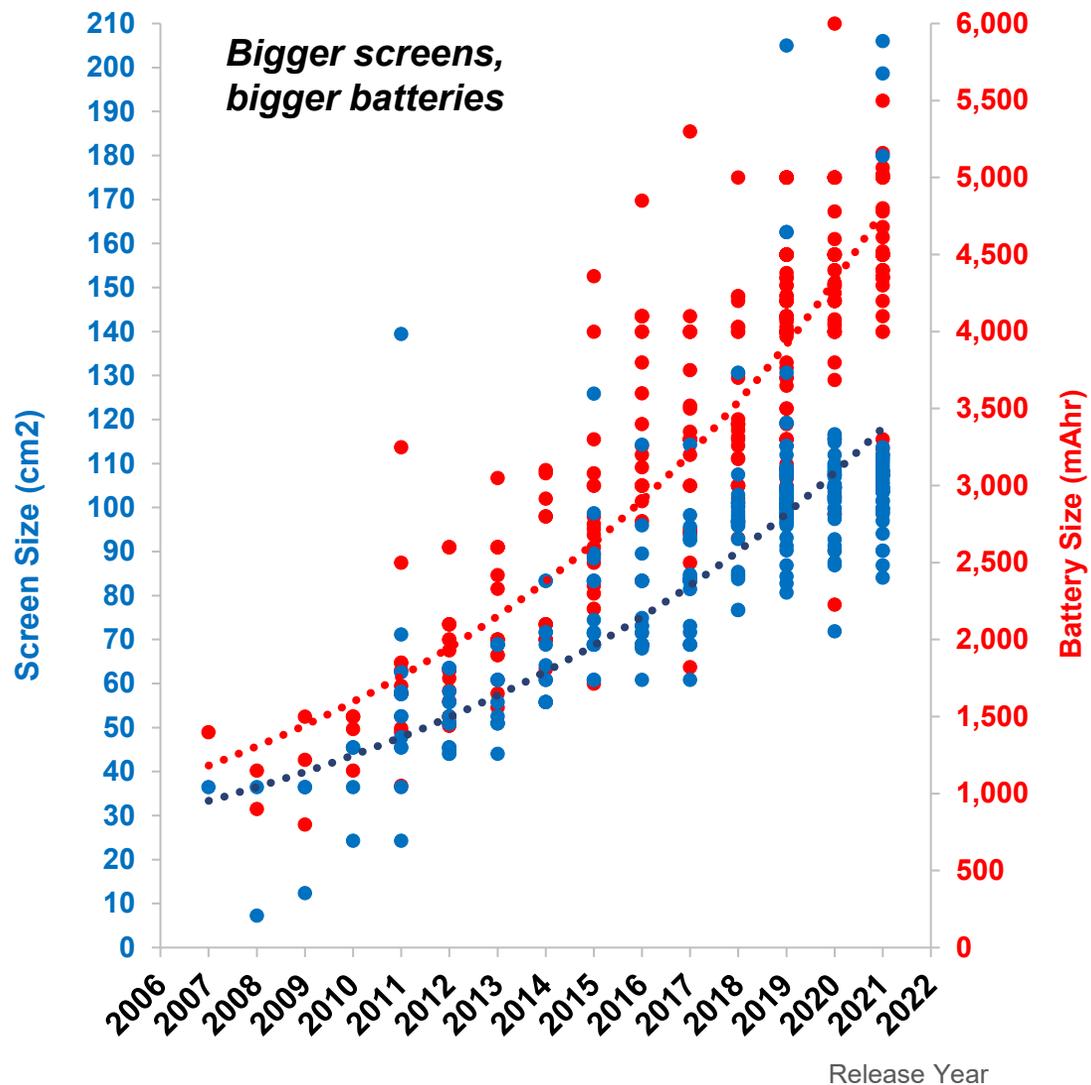
3x

Faster
Charging

20%

Lower
System Cost

Power-Hungry Smartphones Use GaN



Chargers go GaNFast



Tier 1 OEMs



Aftermarket Examples



160+

GaN Chargers In Mass Production

150+

GaN Chargers In Development (MP 2021-2022)

90%+

Mobile OEMs Designing With Navitas GaN ICs

30M+

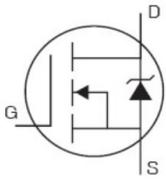
GaN ICs Shipped⁽¹⁾

Zero

GaN Field-Failures⁽¹⁾

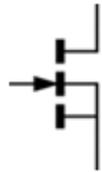
The GaNFast Evolution

Silicon FET



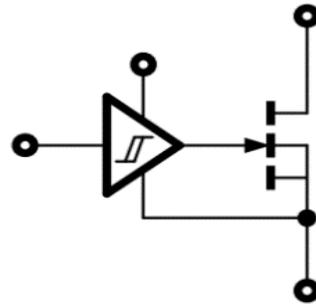
- Old, slow technology
- High Q_g
- High C_{oss}
- $f_{sw} < 100\text{kHz}$

Discrete GaN



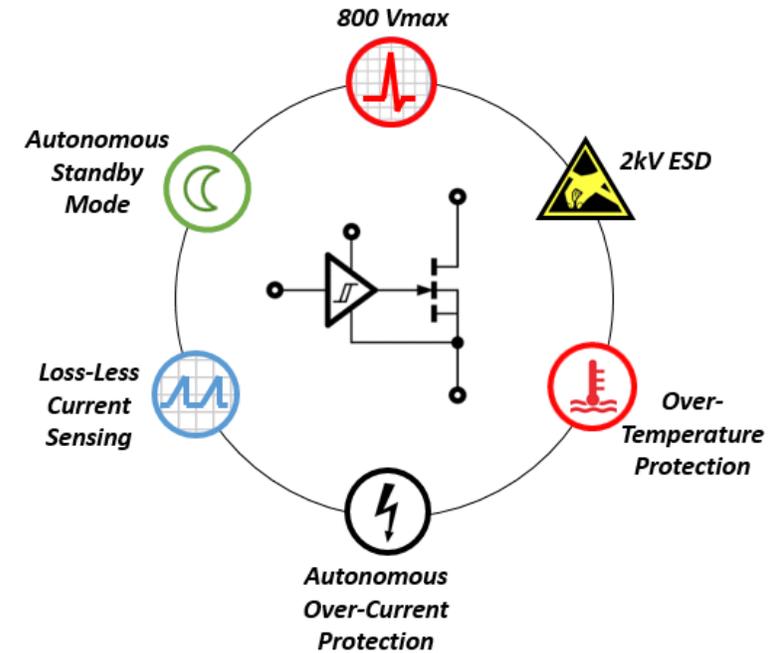
- Exposed gate
- External gate drive
- dV/dt sensitivity
- Layout sensitivity
- ESD sensitivity
- Unknown reliability
- Unknown robustness

GaNFast™



- Internal Gate
- Integrated Gate Drive
- dV/dt Immunity
- Layout Insensitive
- 2KV ESD rating
- Proven Reliability
- Proven Robustness

GaNFast™ with GaNSense™

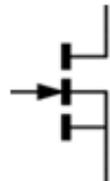
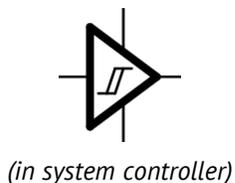


- Autonomous Standby
- Autonomous Protection
- Loss-less Current Sensing
- High Precision
- High Efficiency

Critical Integration: GaNFast

Driver Drive, control & protection	Parasitics Limit speed & efficiency	Power Device Si or GaN	Speed Switching Frequency	Power Density Faster Charging, Smaller Size
---------------------------------------	--	---------------------------	------------------------------	--

Silicon Discrete

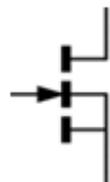
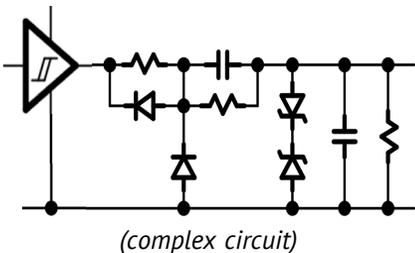


< 100 kHz



<0.5 W/cc

GaN Discrete

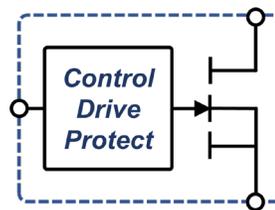


< 200 kHz



<1 W/cc

Navitas GaN IC



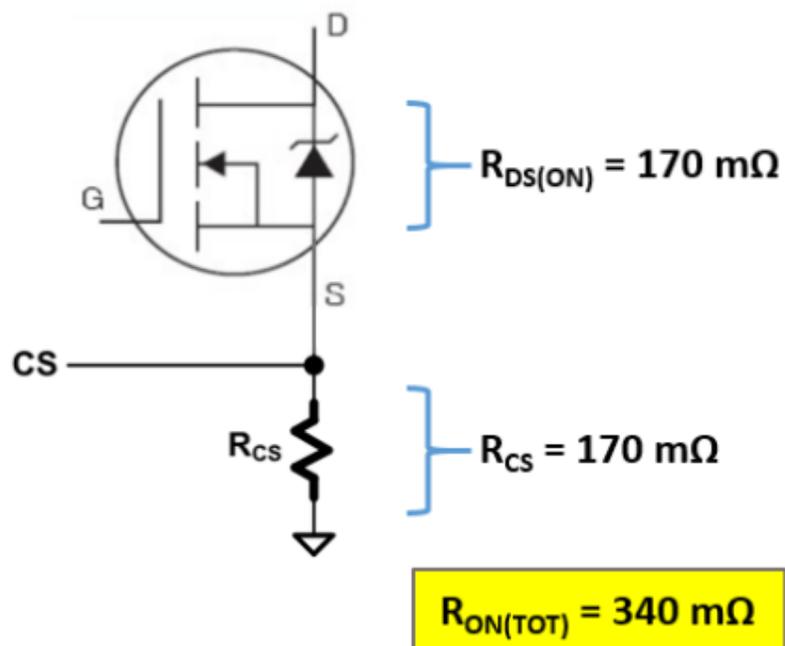
Up to 2 MHz
(3-10x faster)



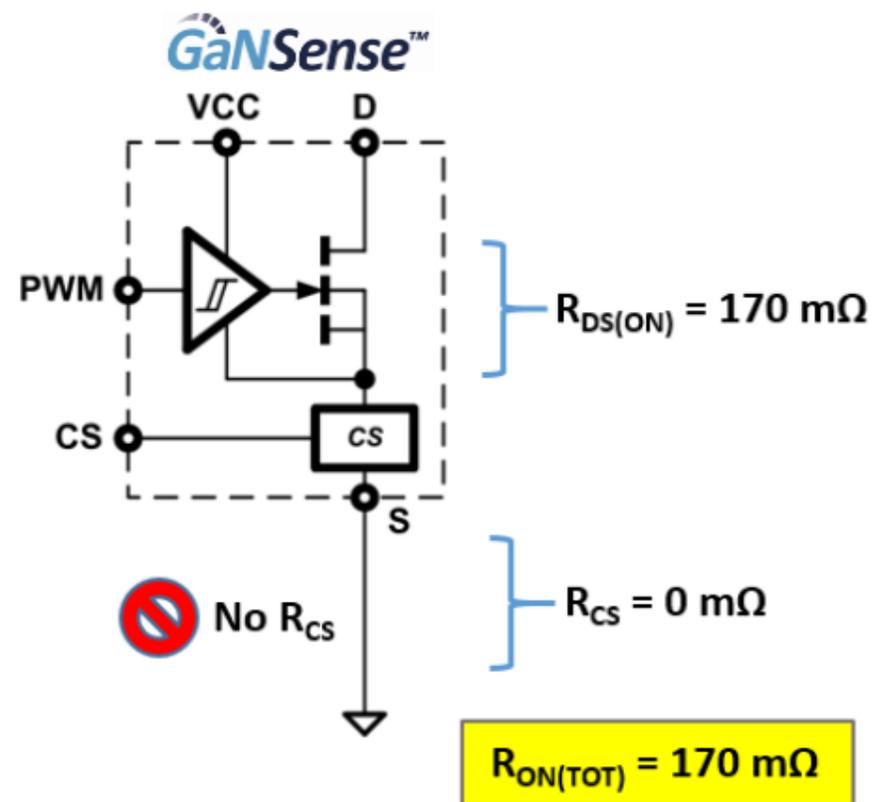
>>1 W/cc

Loss-Less Current Sensing: Why?

External Resistor Sensing Method

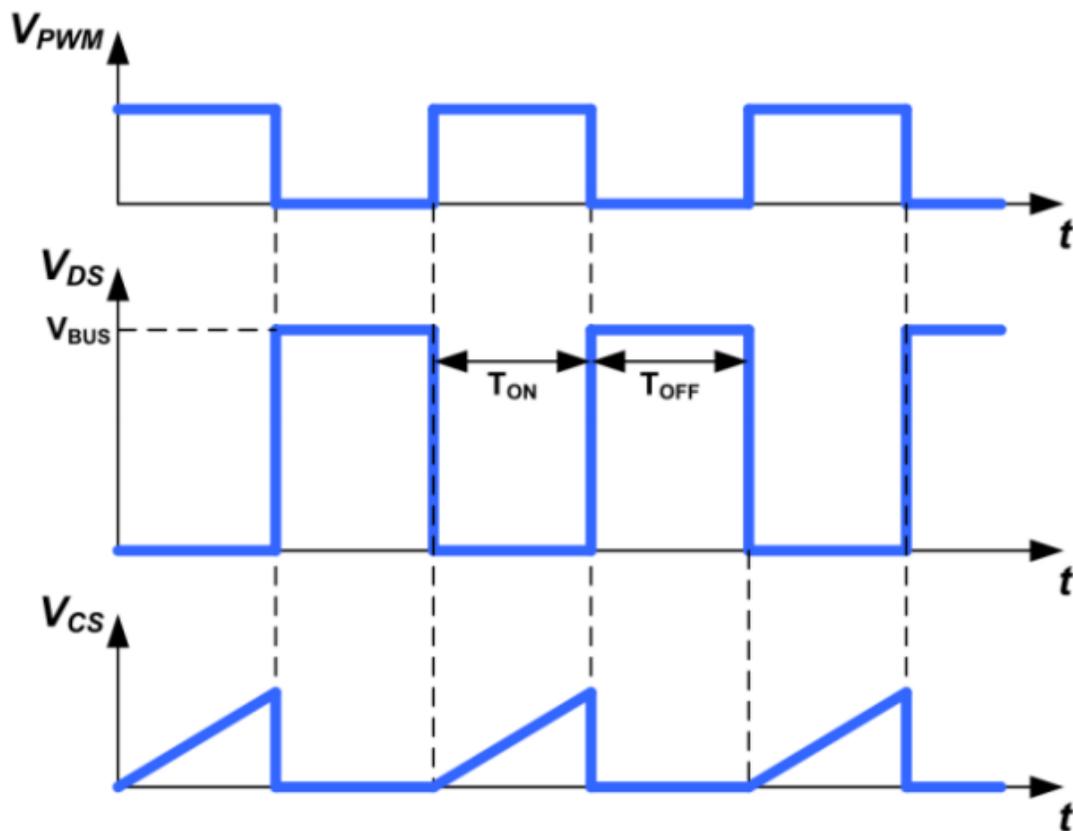
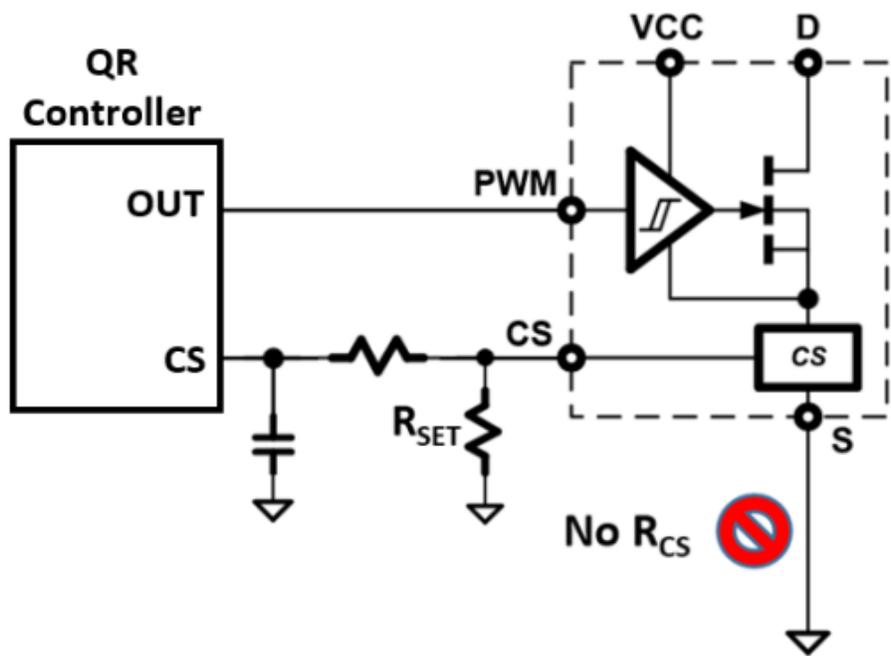


- Reduce $R_{DS(ON_TOTAL)}$ by 50%
- Efficiency increased +0.5%

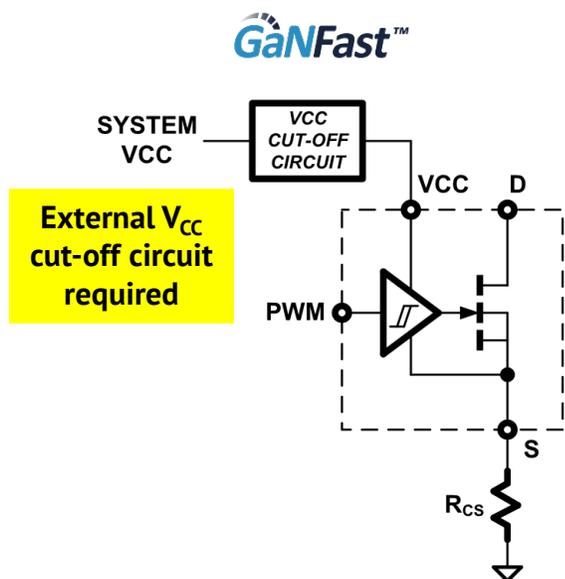


- No R_{CS} PCB hotspot (-85°C)
- No R_{CS} PCB footprint (-30 mm²)

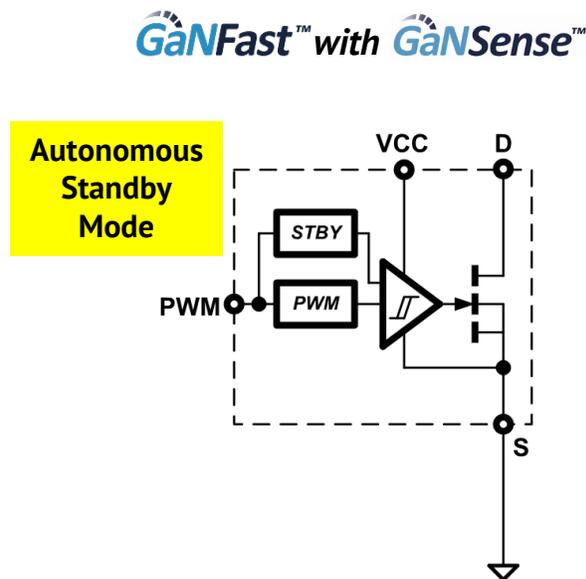
Loss-Less Current Sensing: How?



Autonomous Standby Mode

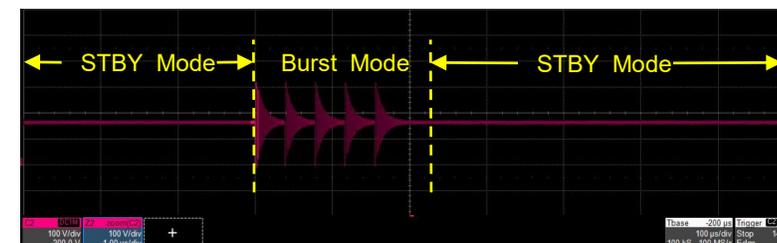


- External V_{CC} cut-off circuit required
- Requires system enable signal



- Autonomous standby mode
- Enters STBY during no PWM
- Fast wake-up at next PWM
- Standby power reduction (-17%)
- Removes 5 components

17% Lower Standby Loss



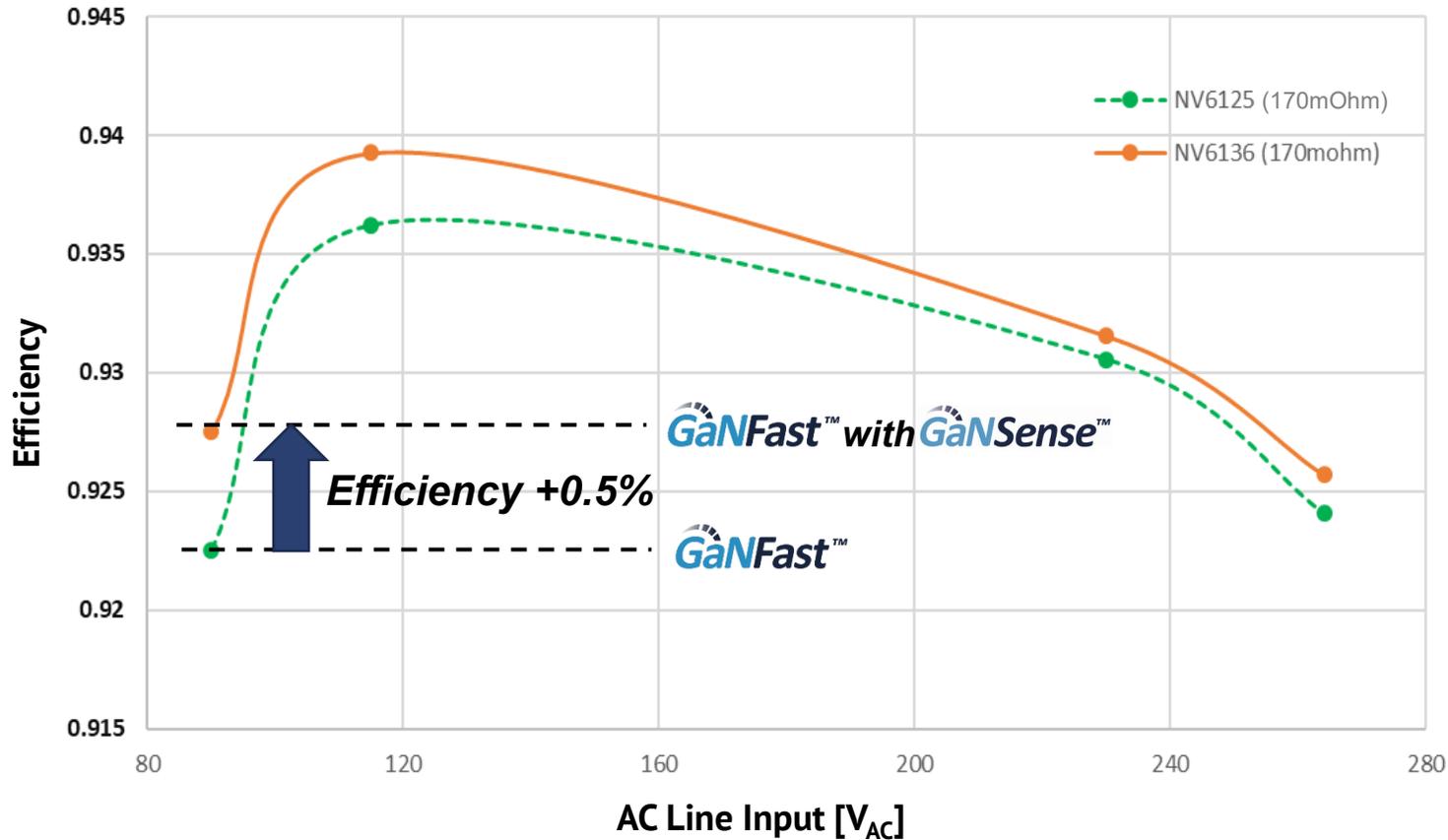
HFQR, no load

P_{IN} (no load)	115 V _{AC}	230 V _{AC}
NV6125	39 mW	40 mW
NV6136	33 mW	33 mW

- Enters STBY during no PWM signal
- Wakes up again at each burst

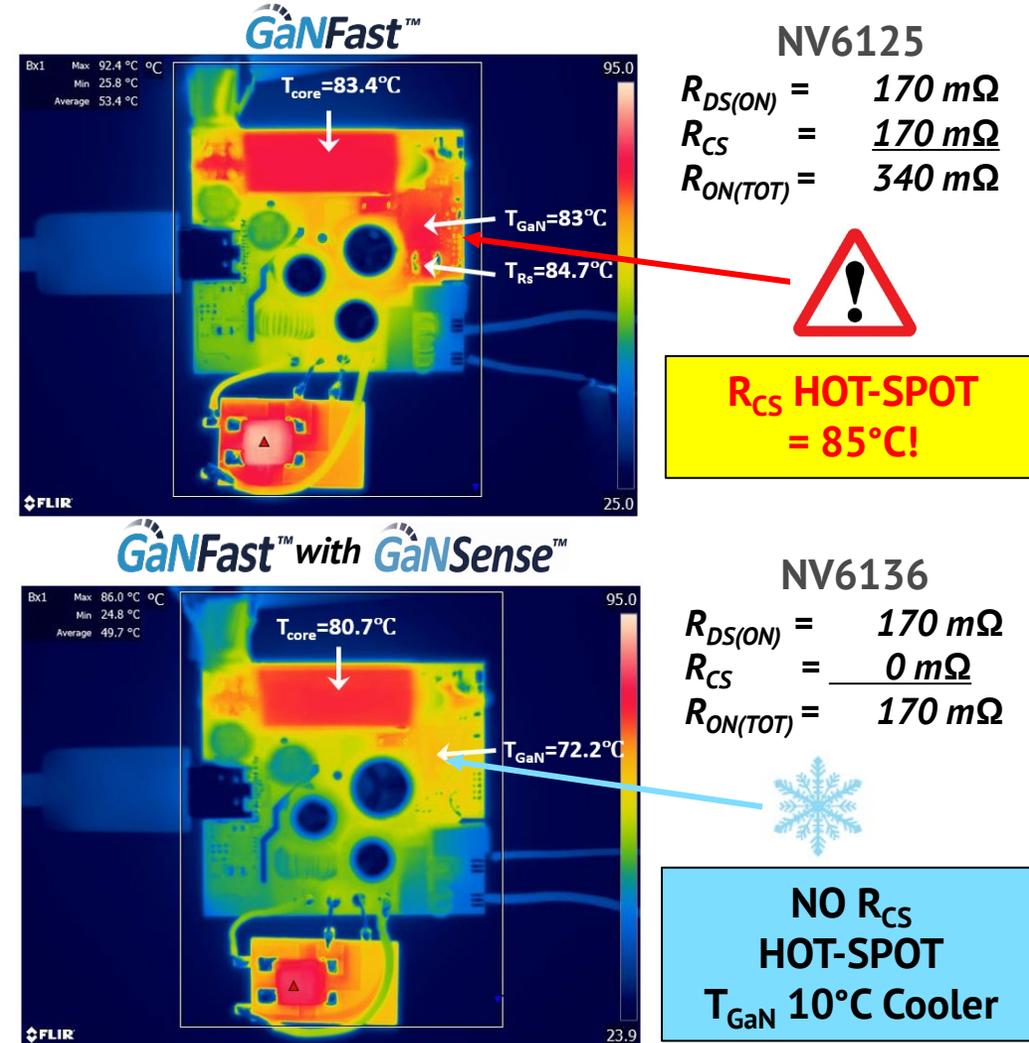
The Efficiency Benefit

Efficiency (60W HFQR, 20V/3A)



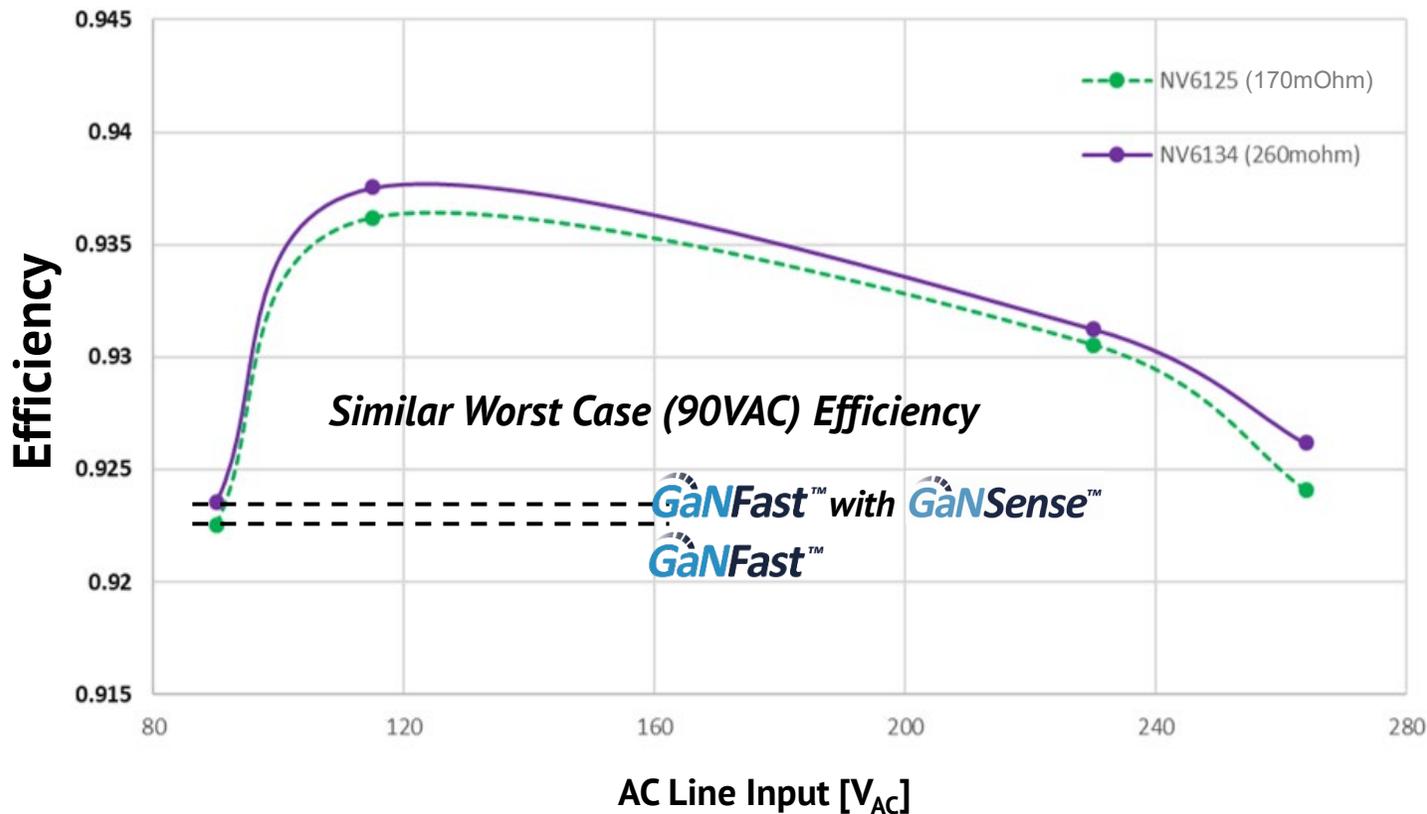
0.5% higher efficiency, same $R_{DS(ON)}$, lower $R_{ON(TOTAL)}$

60W HFQR, 90V_{AC}, 20V/3A, 1 Hour



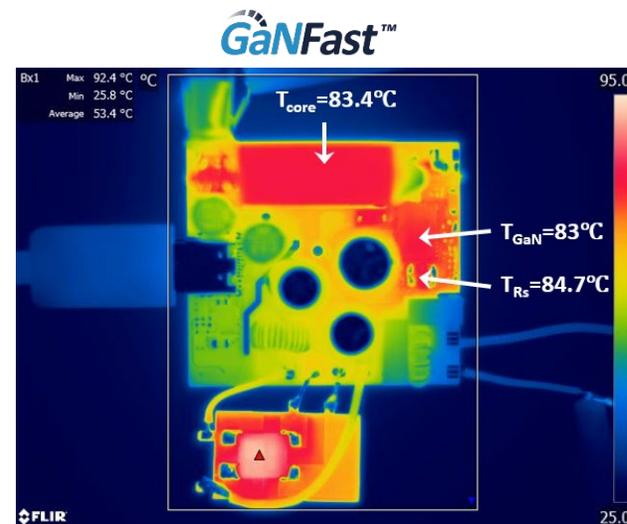
The System Cost Benefit

Efficiency (60W HFQR, 20V/3A)



Same efficiency, smaller chip, same $R_{ON(TOTAL)}$

60W HFQR, 90V_{AC}, 20V/3A, 1 Hour

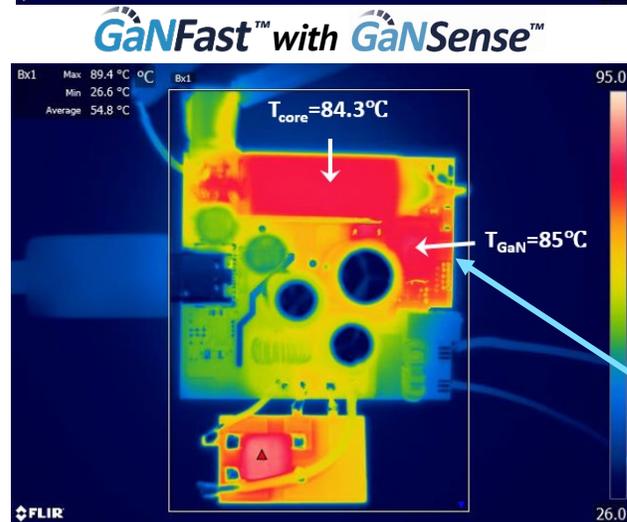


NV6125

$$R_{DS(ON)} = 170 \text{ m}\Omega$$

$$R_{CS} = 170 \text{ m}\Omega$$

$$R_{ON(TOT)} = 340 \text{ m}\Omega$$



NV6134

$$R_{DS(ON)} = 260 \text{ m}\Omega$$

$$R_{CS} = 0 \text{ m}\Omega$$

$$R_{ON(TOT)} = 260 \text{ m}\Omega$$

No R_{CS}
Similar
Temperatures

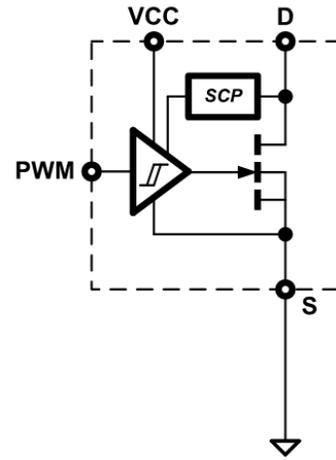
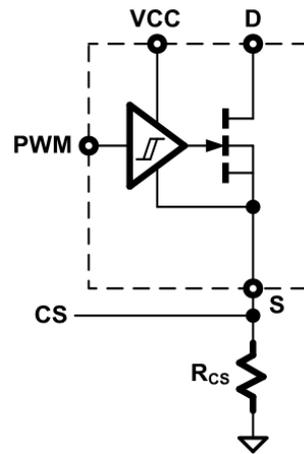
Autonomous Over-Current Protection (OCP)

GaNFast™

GaNFast™ with GaNSense™

Uses QR controller
OCP function

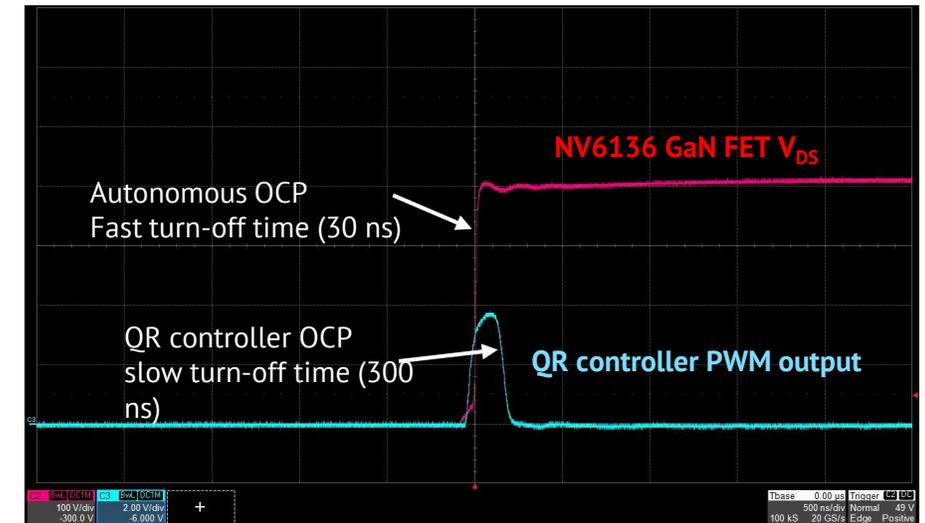
$T_{OCP} = 180 \text{ ns}$



Integrated
SCP function

$T_{OCP} = 30 \text{ ns}$

6x faster protection

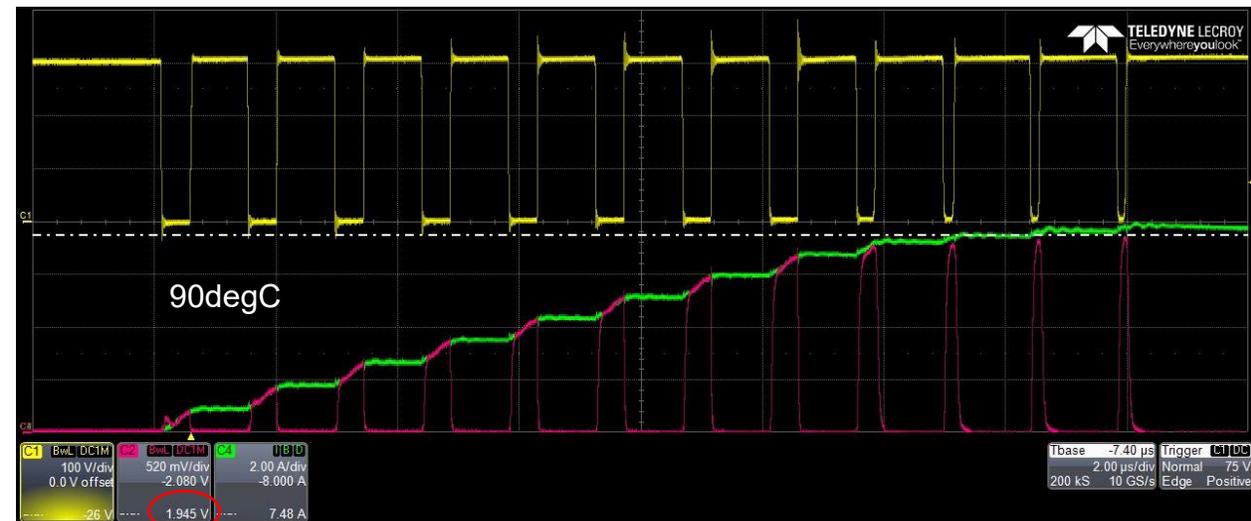
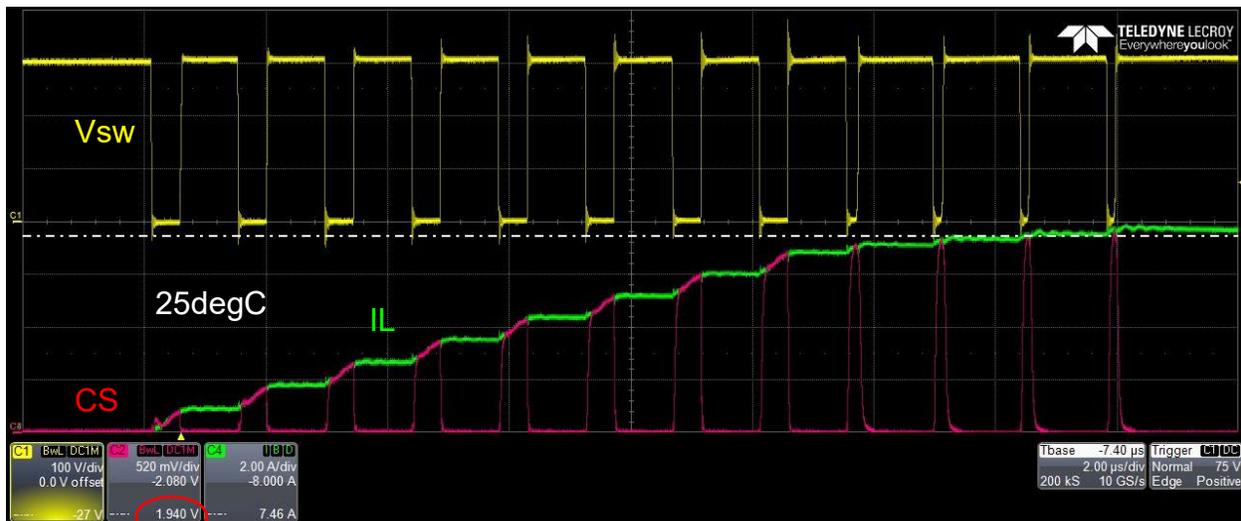


- Existing solutions use ext. R_{CS}
- Filter + controller delay slow

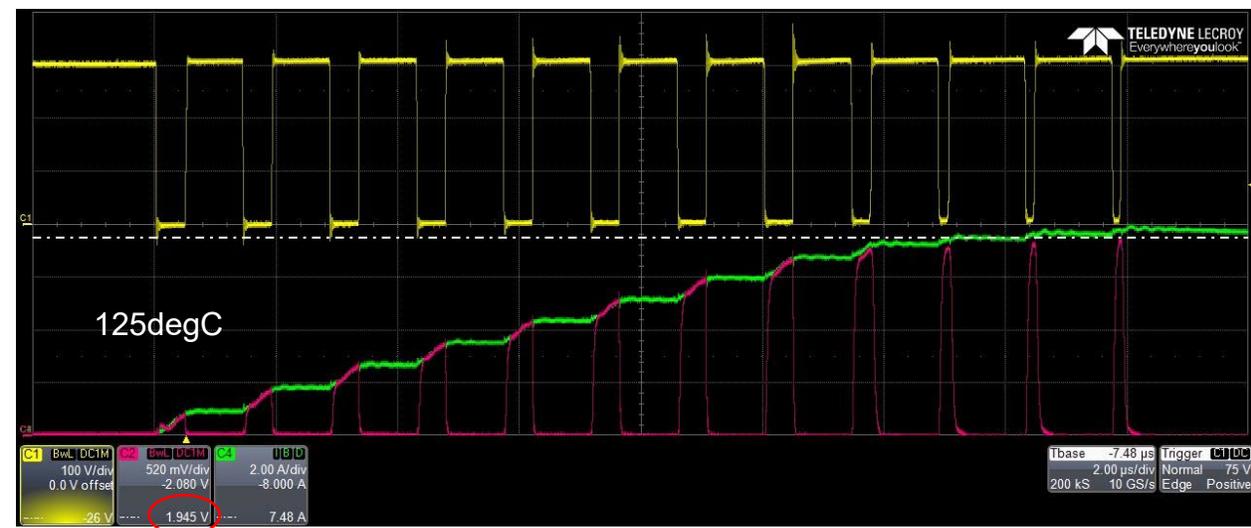
- Autonomous OCP
- Real-time self-protection
- Cycle-by-cycle protection
- Excellent robustness

- QR controller OCP = slow turn-off (180 ns)
- NV6136 OCP = fast turn-off (30 ns)

Over-Current Protection (OCP) cont.

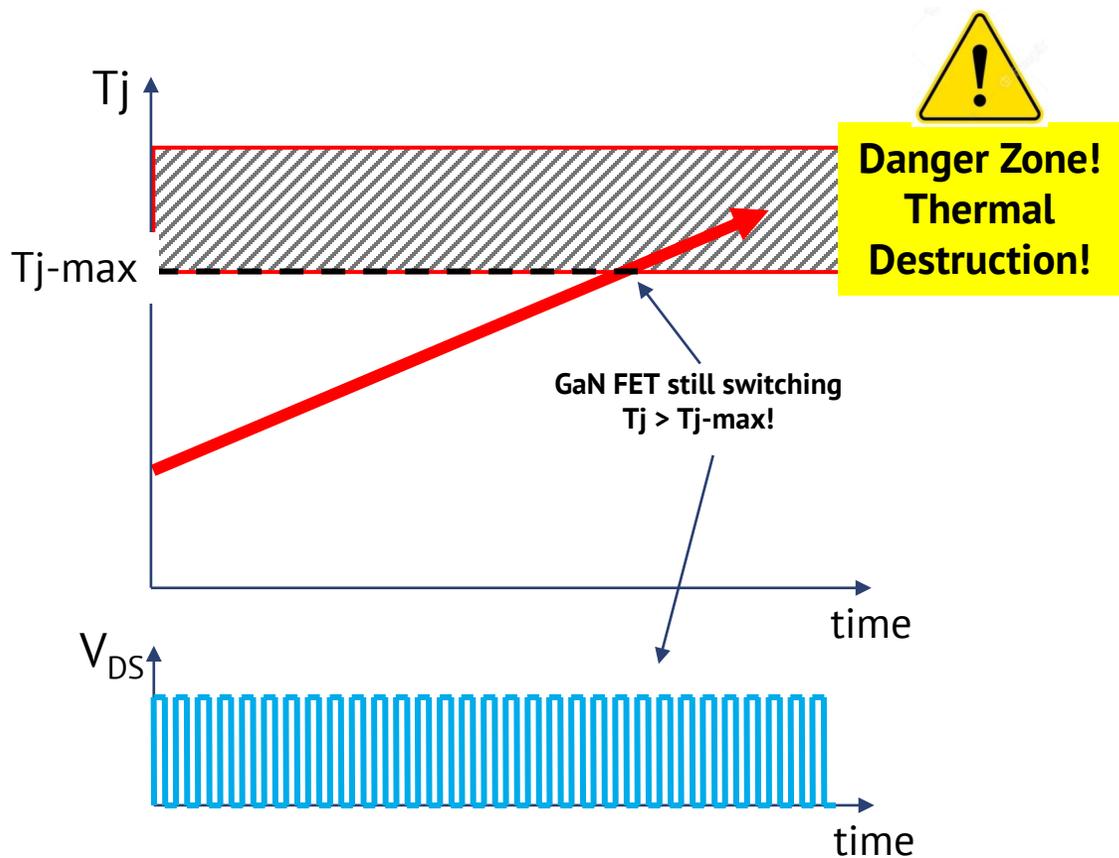


- NV6134A in double pulse tester
- CS signal matches I_{DS} current, independent of temperature
- OCP uses CS signal, and the trip point is consistent over temperature
- OCP is cycle by cycle, and limits inductor current

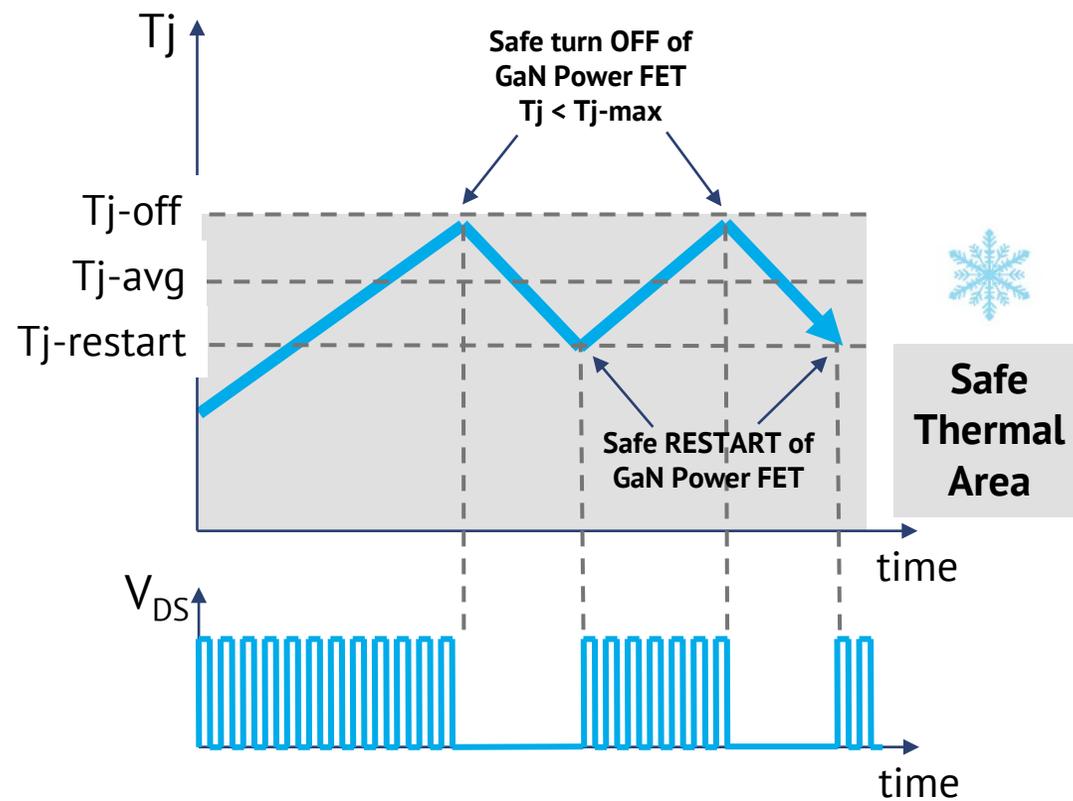


Over-Temperature Protection

Discrete GaN

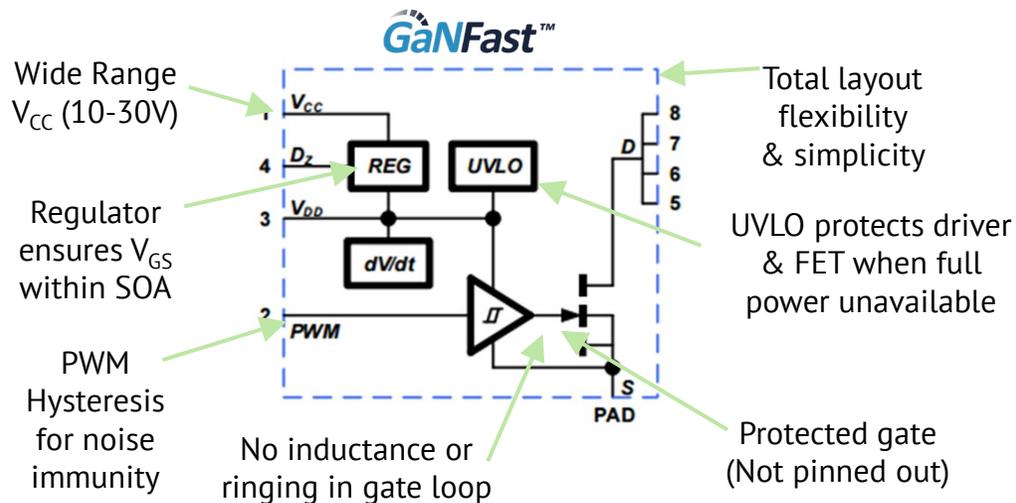


GaNSense IC w/OTP



Leaders in Reliability

Reliability by Design



Unprotected GaN

Navitas GaN Power IC



- Exposed gate
- Faulty switching
- Dangerous ringing & glitching!
- Significant reliability risks



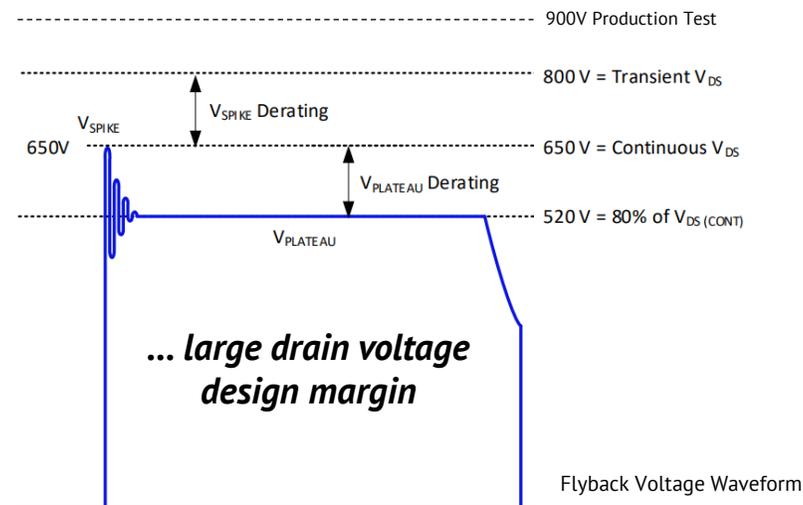
- Integrated gate drive
- Clean switching
- Safe, robust and reliable performance

Reliability

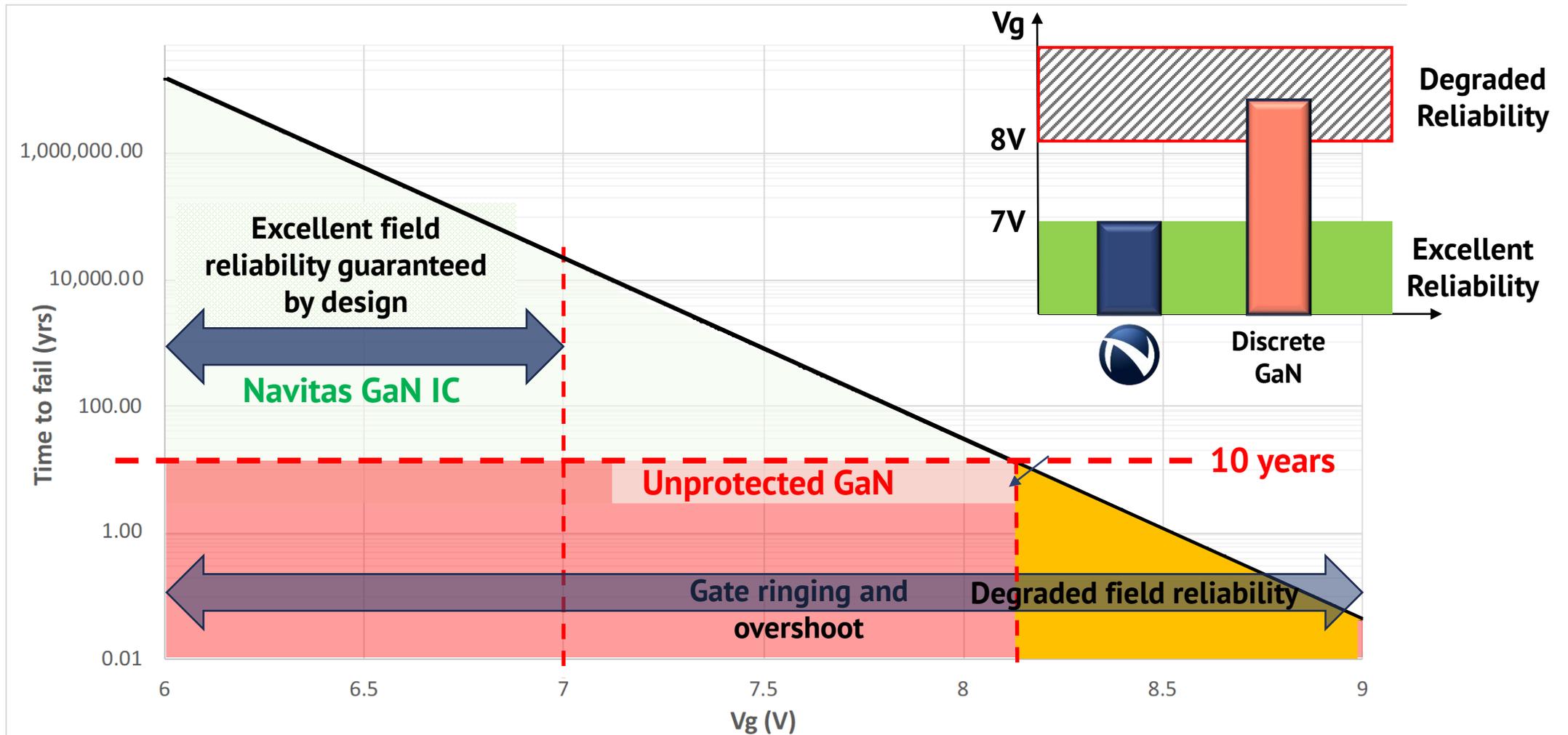
As of October 31st, 2021

30,000,000+ GaNFast power ICs shipped	116B+ Device Hours In the Field
0 Failures	0 ppm
0.16 FIT Rate	5.8B Equivalent Device Hours Tested

Integrated Drain Reliability



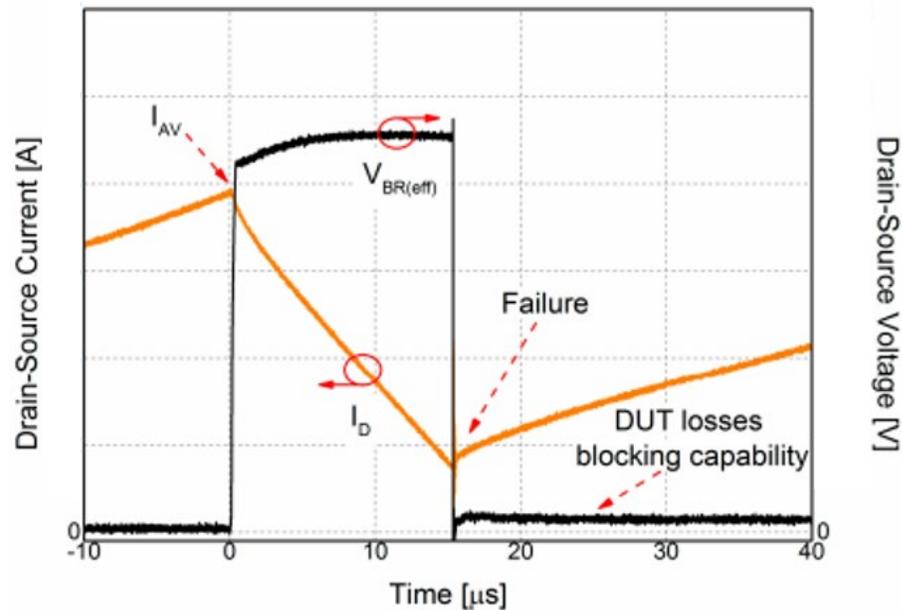
Precise Gate Voltage = Excellent Reliability



- Patented integrated regulator circuit guarantees operation with >>10+ years of estimated life
- Integrated driver eliminates parasitic inductance, delivers precise gate drive and maintains device within SOA

Voltage Surge Testing

Si Avalanche Testing



- Voltage limited by avalanche breakdown
- Large energy loss during overvoltage
- Usually tested only once at final test
- Repetitive avalanche can lead to failure

Navitas GaN IC Surge Testing

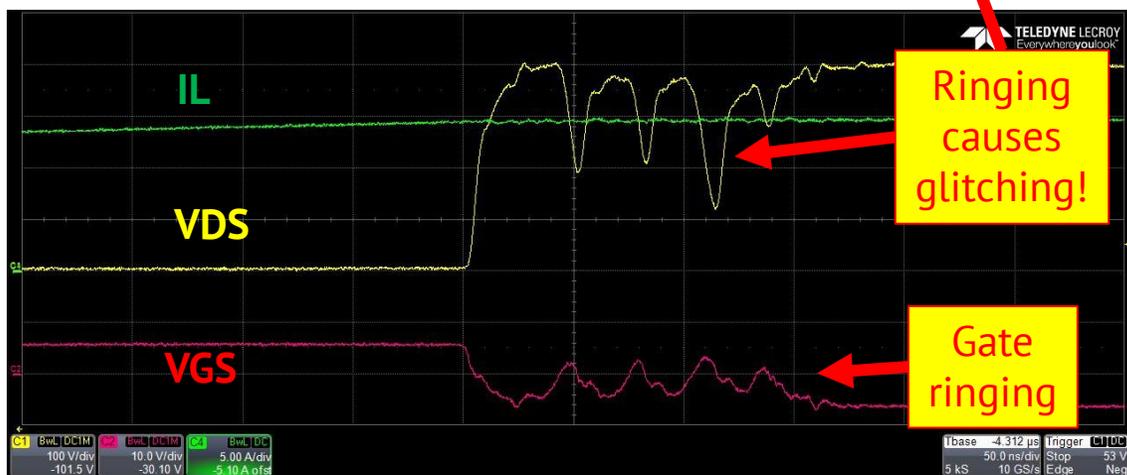
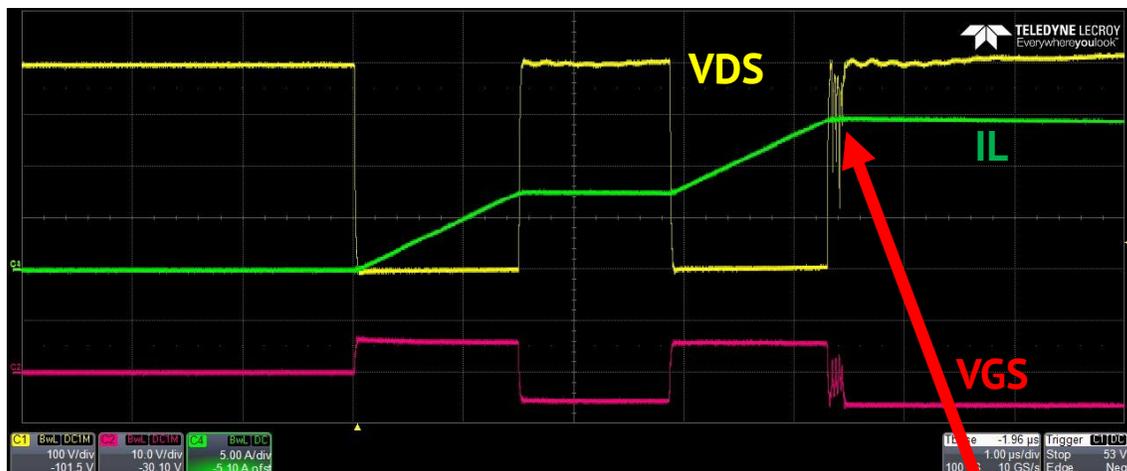


100μs pulse width, V_{DS} = 800 V

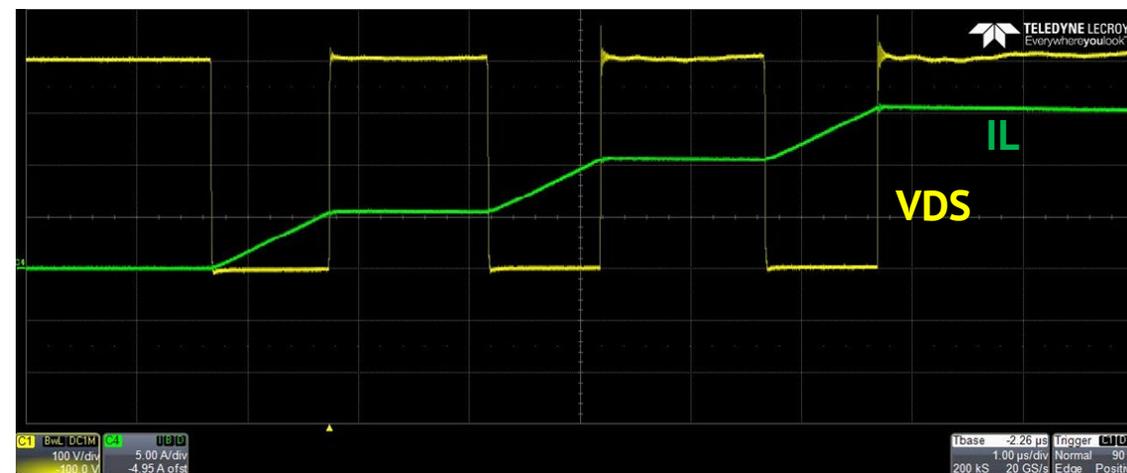
- 3,600,000,000 spikes, no failures!
- Negligible energy loss during overvoltage
- No R_{DS(ON)} shift
- No I_{DSS} shift

Reliable: Double-Pulse Test

Discrete



NV6136 GaNSense



- Clean switching, no ringing and no glitching

- Ringing can lead to gate voltage over-stress, poor gate reliability, reduced lifetime
- Glitching can lead to poor EMI and device failure

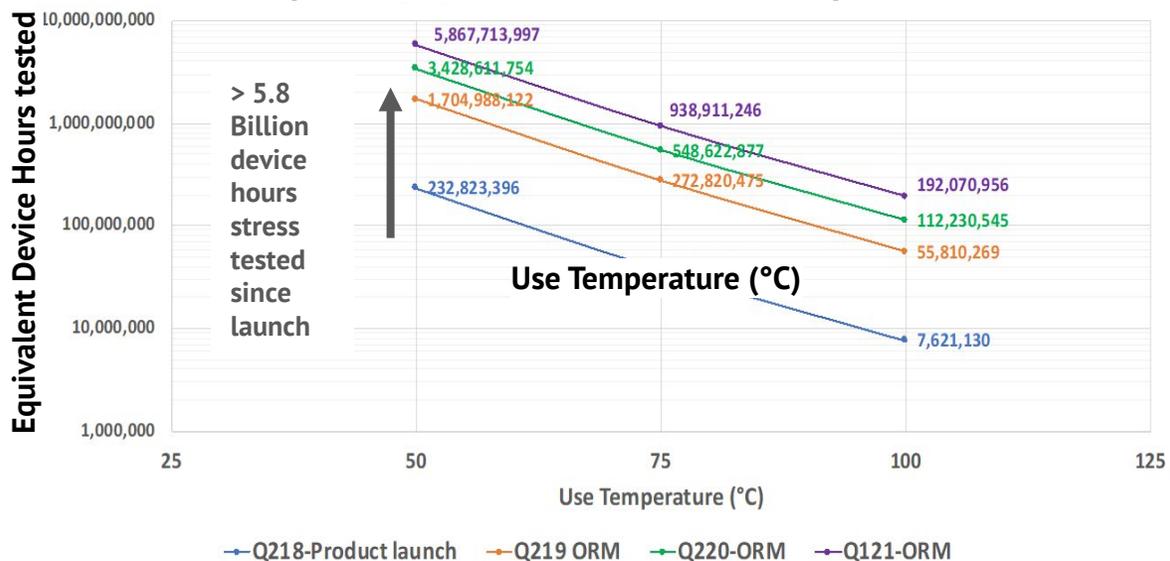
Production Reliability Monitoring

- Reliability monitoring of production material throughout 3 years of production
- 7,276 units tested on high-frequency, soft-switching application-focused stress testing from over 70 fab lots.

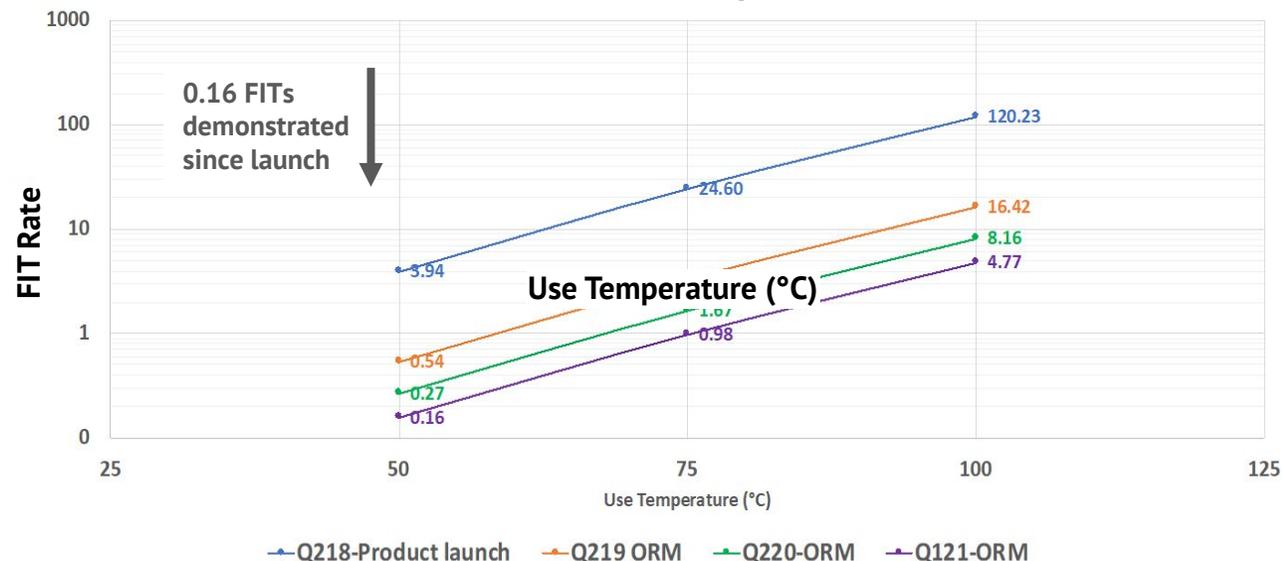
Reliability Statistics

Calculated for High Line condition using HTOL (ZVS) results

Equivalent Device Hours vs. Use Temperature



FIT Rate vs. Use Temperature



GaN Sense Mass Production: 65W

Lenovo YOGA

Charger Power, Output(s)	65W 2CA	65W 2C		
				
Powertrain	Discrete GaN	NV6134 GaNFast with GaN Sense		
Size (cc)	105	75	30%	Smaller
Power Density (W/cc)	0.6	0.9	50%	Higher
Efficiency (%) ⁽¹⁾	89.15%	92.50%	3.4%	Higher
Loss (W)	7.1	4.9	30%	Energy Savings
Drive, Protection Components	19	5	75%	Fewer
PCB Area (mm ²)	83	15	80%	Smaller
T _{CASE} max (°C) ⁽¹⁾	85°C	<77°C	8°C	Cooler



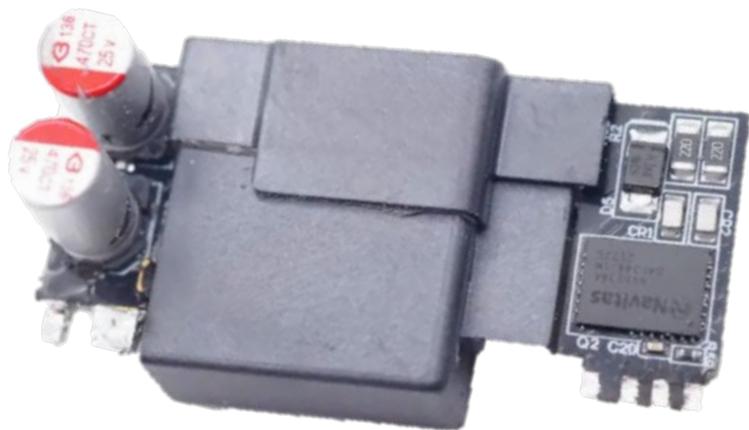
联想 YOGA + 纳微: 4月22日

全芯上市
一起 YOGA



120W Xiaomi GaNFast

- DCM boost PFC:
 - Silergy SY5072B
 - NV6134 GaNFast with GaNSense
- HFQR DC-DC
 - Onsemi NCP1342
 - NV6134 GaNFast with GaNSense
 - Planar transformer (shown)



120W

小米氮化镓充电套装

小巧一点，强大很多



*包装内含Type-C to Type-C数据线(1m)。

120W

GaNFast with GaNSense



- 4,500 mAh battery
- Graphene Li-Ion
- 0-100% in 17 minutes
- 20% smaller

[Read More](#)

Environment / Reduced CO₂ Emissions

4x-10x lower component CO₂ footprint than silicon

28% lower lifetime CO₂ footprint for chargers / adapters

Accelerate transition from ICE to EV by 3 years,
saving 20%/yr of road sector emissions by 2050

GaN addresses 2.6 Gton / year by 2050

Every
GaNFast™ power IC
shipped saves
4 kg CO₂



PARIS2015
UN CLIMATE CHANGE CONFERENCE
COP21·CMP11



Join the GaN Generation!



www.navitassemi.com
www.ganfast.com



Let's go **GaNFast**™